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Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

| Details | |
|--------------------------------|--|
| Product Status | Obsolete |
| Number of LABs/CLBs | 262400 |
| Number of Logic Elements/Cells | 695000 |
| Total RAM Bits | 51200000 |
| Number of I/O | 840 |
| Number of Gates | - |
| Voltage - Supply | 0.82V ~ 0.88V |
| Mounting Type | Surface Mount |
| Operating Temperature | -40°C ~ 100°C (TJ) |
| Package / Case | 1932-BBGA, FCBGA |
| Supplier Device Package | 1932-FBGA, FC (45x45) |
| Purchase URL | https://www.e-xfl.com/product-detail/intel/5sgsed8n2f45i3l |

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Recommended Operating Conditions

This section lists the functional operating limits for the AC and DC parameters for Stratix V devices. Table 6 lists the steady-state voltage and current values expected from Stratix V devices. Power supply ramps must all be strictly monotonic, without plateaus.

Table 6. Recommended Operating Conditions for Stratix V Devices (Part 1 of 2)

| Symbol | Description | Condition | Min ⁽⁴⁾ | Тур | Max ⁽⁴⁾ | Unit |
|----------------------------------|--|------------|--------------------|------|--------------------|------|
| | Core voltage and periphery circuitry power supply (C1, C2, I2, and I3YY speed grades) | _ | 0.87 | 0.9 | 0.93 | V |
| V _{CC} | Core voltage and periphery circuitry power supply (C2L, C3, C4, I2L, I3, I3L, and I4 speed grades) (3) | _ | 0.82 | 0.85 | 0.88 | V |
| V _{CCPT} | Power supply for programmable power technology | _ | 1.45 | 1.50 | 1.55 | V |
| V _{CC_AUX} | Auxiliary supply for the programmable power technology | _ | 2.375 | 2.5 | 2.625 | V |
| V (1) | I/O pre-driver (3.0 V) power supply | | 2.85 | 3.0 | 3.15 | V |
| V _{CCPD} ⁽¹⁾ | I/O pre-driver (2.5 V) power supply | | 2.375 | 2.5 | 2.625 | V |
| | I/O buffers (3.0 V) power supply | _ | 2.85 | 3.0 | 3.15 | ٧ |
| | I/O buffers (2.5 V) power supply | _ | 2.375 | 2.5 | 2.625 | V |
| V _{CCIO} | I/O buffers (1.8 V) power supply | _ | 1.71 | 1.8 | 1.89 | ٧ |
| | I/O buffers (1.5 V) power supply | _ | 1.425 | 1.5 | 1.575 | V |
| | I/O buffers (1.35 V) power supply | | 1.283 | 1.35 | 1.45 | V |
| | I/O buffers (1.25 V) power supply | | 1.19 | 1.25 | 1.31 | V |
| | I/O buffers (1.2 V) power supply | _ | 1.14 | 1.2 | 1.26 | V |
| | Configuration pins (3.0 V) power supply | | 2.85 | 3.0 | 3.15 | V |
| V_{CCPGM} | Configuration pins (2.5 V) power supply | _ | 2.375 | 2.5 | 2.625 | V |
| | Configuration pins (1.8 V) power supply | _ | 1.71 | 1.8 | 1.89 | V |
| V _{CCA_FPLL} | PLL analog voltage regulator power supply | | 2.375 | 2.5 | 2.625 | V |
| V _{CCD_FPLL} | PLL digital voltage regulator power supply | | 1.45 | 1.5 | 1.55 | V |
| V _{CCBAT} (2) | Battery back-up power supply (For design security volatile key register) | _ | 1.2 | _ | 3.0 | V |
| V _I | DC input voltage | _ | -0.5 | _ | 3.6 | V |
| V ₀ | Output voltage | _ | 0 | _ | V _{CCIO} | V |
| т. | Operating junction temperature | Commercial | 0 | _ | 85 | °C |
| T _J | Operating junction temperature | Industrial | -40 | _ | 100 | °C |

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Table 6. Recommended Operating Conditions for Stratix V Devices (Part 2 of 2)

| Symbol | Description | Condition | Min ⁽⁴⁾ | Тур | Max ⁽⁴⁾ | Unit |
|-----------------------------|------------------------|--------------|--------------------|------|--------------------|------|
| t | Power supply ramp time | Standard POR | 200 μs | _ | 100 ms | _ |
| RAMP Power supply ramp time | Fast POR | 200 μs | _ | 4 ms | _ | |

Notes to Table 6:

- (1) V_{CCPD} must be 2.5 V when V_{CCIO} is 2.5, 1.8, 1.5, 1.35, 1.25 or 1.2 V. V_{CCPD} must be 3.0 V when V_{CCIO} is 3.0 V.
- (2) If you do not use the design security feature in Stratix V devices, connect V_{CCBAT} to a 1.2- to 3.0-V power supply. Stratix V power-on-reset (POR) circuitry monitors V_{CCBAT}. Stratix V devices will not exit POR if V_{CCBAT} stays at logic low.
- (3) C2L and I2L can also be run at 0.90 V for legacy boards that were designed for the C2 and I2 speed grades.
- (4) The power supply value describes the budget for the DC (static) power supply tolerance and does not include the dynamic tolerance requirements. Refer to the PDN tool for the additional budget for the dynamic tolerance requirements.

Table 7 lists the transceiver power supply recommended operating conditions for Stratix V GX, GS, and GT devices.

Table 7. Recommended Transceiver Power Supply Operating Conditions for Stratix V GX, GS, and GT Devices (Part 1 of 2)

| Symbol | Description | Devices | Minimum ⁽⁴⁾ | Typical | Maximum ⁽⁴⁾ | Unit |
|------------------------|---|------------|------------------------|---------|------------------------|------|
| V _{CCA_GXBL} | Transceiver channel PLL power supply (left | GX, GS, GT | 2.85 | 3.0 | 3.15 | V |
| (1), (3) | side) | ७४, ७७, ७१ | 2.375 | 2.5 | 2.625 | V |
| V _{CCA_GXBR} | Transceiver channel PLL power supply (right | GX, GS | 2.85 | 3.0 | 3.15 | V |
| $(1), (\overline{3})$ | side) | রম, রহ | 2.375 | 2.5 | 2.625 | V |
| V _{CCA_GTBR} | Transceiver channel PLL power supply (right side) | GT | 2.85 | 3.0 | 3.15 | V |
| | Transceiver hard IP power supply (left side; C1, C2, I2, and I3YY speed grades) | GX, GS, GT | 0.87 | 0.9 | 0.93 | V |
| V _{CCHIP_L} | Transceiver hard IP power supply (left side; C2L, C3, C4, I2L, I3, I3L, and I4 speed grades) | GX, GS, GT | 0.82 | 0.85 | 0.88 | V |
| | Transceiver hard IP power supply (right side; C1, C2, I2, and I3YY speed grades) | GX, GS, GT | 0.87 | 0.9 | 0.93 | V |
| V_{CCHIP_R} | Transceiver hard IP power supply (right side; C2L, C3, C4, I2L, I3, I3L, and I4 speed grades) | GX, GS, GT | 0.82 | 0.85 | 0.88 | V |
| | Transceiver PCS power supply (left side; C1, C2, I2, and I3YY speed grades) | GX, GS, GT | 0.87 | 0.9 | 0.93 | V |
| V _{CCHSSI_L} | Transceiver PCS power supply (left side; C2L, C3, C4, I2L, I3, I3L, and I4 speed grades) | GX, GS, GT | 0.82 | 0.85 | 0.88 | V |
| | Transceiver PCS power supply (right side; C1, C2, I2, and I3YY speed grades) | GX, GS, GT | 0.87 | 0.9 | 0.93 | V |
| $V_{\text{CCHSSI_R}}$ | Transceiver PCS power supply (right side; C2L, C3, C4, I2L, I3, I3L, and I4 speed grades) | GX, GS, GT | 0.82 | 0.85 | 0.88 | V |
| | | | 0.82 | 0.85 | 0.88 | |
| V _{CCR_GXBL} | Receiver analog power supply (left side) | GX, GS, GT | 0.87 | 0.90 | 0.93 | V |
| (2) | Treceiver arialog power supply (left side) | un, us, ui | 0.97 | 1.0 | 1.03 | V |
| | | | 1.03 | 1.05 | 1.07 | |

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Table 8 shows the transceiver power supply voltage requirements for various conditions.

Table 8. Transceiver Power Supply Voltage Requirements

| Conditions | Core Speed Grade | VCCR_GXB & VCCT_GXB (2) | VCCA_GXB | VCCH_GXB | Unit |
|--|-----------------------------------|-------------------------|----------|----------|------|
| If BOTH of the following conditions are true: | | | | | |
| ■ Data rate > 10.3 Gbps. | All | 1.05 | | | |
| ■ DFE is used. | | | | | |
| If ANY of the following conditions are true (1): | | | 3.0 | | |
| ATX PLL is used. | | | | | |
| ■ Data rate > 6.5Gbps. | All | 1.0 | | | |
| ■ DFE (data rate ≤ 10.3 Gbps), AEQ, or EyeQ feature is used. | | | | 1.5 | V |
| If ALL of the following | C1, C2, I2, and I3YY | 0.90 | 2.5 | | |
| conditions are true: ATX PLL is not used. | | | | | |
| ■ Data rate ≤ 6.5Gbps. | C2L, C3, C4, I2L, I3, I3L, and I4 | 0.85 | 2.5 | | |
| DFE, AEQ, and EyeQ are not used. | | | | | |

Notes to Table 8:

- (1) Choose this power supply voltage requirement option if you plan to upgrade your design later with any of the listed conditions.
- (2) If the VCCR_GXB and VCCT_GXB supplies are set to 1.0 V or 1.05 V, they cannot be shared with the VCC core supply. If the VCCR_GXB and VCCT_GXB are set to either 0.90 V or 0.85 V, they can be shared with the VCC core supply.

DC Characteristics

This section lists the supply current, I/O pin leakage current, input pin capacitance, on-chip termination tolerance, and hot socketing specifications.

Supply Current

Supply current is the current drawn from the respective power rails used for power budgeting. Use the Excel-based Early Power Estimator (EPE) to get supply current estimates for your design because these currents vary greatly with the resources you use.

For more information about power estimation tools, refer to the *PowerPlay Early Power Estimator User Guide* and the *PowerPlay Power Analysis* chapter in the *Quartus II Handbook*.

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Table 11. OCT Calibration Accuracy Specifications for Stratix V Devices (1) (Part 2 of 2)

| | | | Calibration Accuracy | | | | |
|--|--|--|----------------------|------------|----------------|------------|------|
| Symbol | Description | Conditions | C1 | C2,I2 | C3,I3, I3YY | C4,I4 | Unit |
| 50-Ω R _S | Internal series termination with calibration (50- Ω setting) | V _{CCIO} = 3.0, 2.5, 1.8, 1.5, 1.2 V | ±15 | ±15 | ±15 | ±15 | % |
| $34\text{-}\Omega$ and $40\text{-}\Omega$ R_S | Internal series termination with calibration (34- Ω and 40- Ω setting) | V _{CCIO} = 1.5, 1.35, 1.25, 1.2 V | ±15 | ±15 | ±15 | ±15 | % |
| 48 - Ω , 60 - Ω , 80 - Ω , and 240 - Ω R _S | Internal series termination with calibration (48- Ω , 60- Ω , 80- Ω , and 240- Ω setting) | V _{CCIO} = 1.2 V | ±15 | ±15 | ±15 | ±15 | % |
| 50-Ω R _T | Internal parallel termination with calibration (50-Ω setting) | V _{CCIO} = 2.5, 1.8, 1.5, 1.2 V | -10 to +40 | -10 to +40 | -10 to +40 | -10 to +40 | % |
| $\begin{array}{c} 20\text{-}\Omega,30\text{-}\Omega,\\ 40\text{-}\Omega,60\text{-}\Omega,\\ \text{and}\\ 120\text{-}\OmegaR_T \end{array}$ | Internal parallel termination with calibration (20- Ω , 30- Ω , 40- Ω , 60- Ω , and 120- Ω setting) | V _{CCIO} = 1.5, 1.35, 1.25 V | -10 to +40 | -10 to +40 | -10 to +40 | -10 to +40 | % |
| 60- Ω and 120- Ω R _T | Internal parallel termination with calibration (60- Ω and 120- Ω setting) | V _{CCIO} = 1.2 | -10 to +40 | -10 to +40 | -10 to +40 | -10 to +40 | % |
| $\begin{array}{c} \textbf{25-}\Omega \\ \textbf{R}_{S_left_shift} \end{array}$ | Internal left shift series termination with calibration (25- Ω R _{S_left_shift} setting) | V _{CCIO} = 3.0, 2.5, 1.8, 1.5, 1.2 V | ±15 | ±15 | ±15 | ±15 | % |

Note to Table 11:

Table 12 lists the Stratix V OCT without calibration resistance tolerance to PVT changes.

Table 12. OCT Without Calibration Resistance Tolerance Specifications for Stratix V Devices (Part 1 of 2)

| | | | Resistance Tolerance | | | | |
|-----------------------------|--|-----------------------------------|----------------------|-------|-----------------|--------|------|
| Symbol Description Conditi | | Conditions | C1 | C2,I2 | C3, I3, I3YY | C4, I4 | Unit |
| 25-Ω R, 50-Ω R _S | Internal series termination without calibration (25- Ω setting) | V _{CCIO} = 3.0 and 2.5 V | ±30 | ±30 | ±40 | ±40 | % |
| 25-Ω R _S | Internal series termination without calibration (25- Ω setting) | V _{CCIO} = 1.8 and 1.5 V | ±30 | ±30 | ±40 | ±40 | % |
| 25-Ω R _S | Internal series termination without calibration (25- Ω setting) | V _{CCIO} = 1.2 V | ±35 | ±35 | ±50 | ±50 | % |

⁽¹⁾ OCT calibration accuracy is valid at the time of calibration only.

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| | | | Resistance Tolerance | | | | |
|----------------------|--|-----------------------------------|----------------------|-------|-----------------|--------|------|
| Symbol | Description | Conditions | C1 | C2,I2 | C3, I3, I3YY | C4, I4 | Unit |
| 50-Ω R _S | Internal series termination without calibration (50- Ω setting) | V _{CCIO} = 1.8 and 1.5 V | ±30 | ±30 | ±40 | ±40 | % |
| 50-Ω R _S | Internal series termination without calibration (50- Ω setting) | V _{CCIO} = 1.2 V | ±35 | ±35 | ±50 | ±50 | % |
| 100-Ω R _D | Internal differential termination (100-Ω setting) | V _{CCPD} = 2.5 V | ±25 | ±25 | ±25 | ±25 | % |

Calibration accuracy for the calibrated series and parallel OCTs are applicable at the moment of calibration. When voltage and temperature conditions change after calibration, the tolerance may change.

OCT calibration is automatically performed at power-up for OCT-enabled I/Os. Table 13 lists the OCT variation with temperature and voltage after power-up calibration. Use Table 13 to determine the OCT variation after power-up calibration and Equation 1 to determine the OCT variation without recalibration.

Equation 1. OCT Variation Without Recalibration for Stratix V Devices (1), (2), (3), (4), (5), (6)

$$R_{OCT} = R_{SCAL} \Big(1 + \langle \frac{dR}{dT} \times \Delta T \rangle \pm \langle \frac{dR}{dV} \times \Delta V \rangle \Big)$$

Notes to Equation 1:

- (1) The R_{OCT} value shows the range of OCT resistance with the variation of temperature and V_{CCIO} .
- (2) R_{SCAL} is the OCT resistance value at power-up.
- (3) ΔT is the variation of temperature with respect to the temperature at power-up.
- (4) ΔV is the variation of voltage with respect to the V_{CCIO} at power-up.
- (5) dR/dT is the percentage change of R_{SCAL} with temperature.
- (6) dR/dV is the percentage change of R_{SCAL} with voltage.

Table 13 lists the on-chip termination variation after power-up calibration.

Table 13. OCT Variation after Power-Up Calibration for Stratix V Devices (Part 1 of 2) (1)

| Symbol | Description | V _{CCIO} (V) | Typical | Unit |
|--------|--|-----------------------|---------|------|
| | OCT variation with voltage without recalibration | 3.0 | 0.0297 | |
| | | 2.5 | 0.0344 | |
| dR/dV | | 1.8 | 0.0499 | %/mV |
| | | 1.5 | 0.0744 | |
| | | 1.2 | 0.1241 | |

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Table 13. OCT Variation after Power-Up Calibration for Stratix V Devices (Part 2 of 2) (1)

| Symbol | Description | V _{CCIO} (V) | Typical | Unit |
|--------|--|-----------------------|---------|------|
| | | 3.0 | 0.189 | |
| | OCT variation with temperature without recalibration | 2.5 | 0.208 | |
| dR/dT | | 1.8 | 0.266 | %/°C |
| | | 1.5 | 0.273 | 1 |
| | | 1.2 | 0.317 | |

Note to Table 13:

(1) Valid for a V_{CCIO} range of $\pm 5\%$ and a temperature range of 0° to $85^\circ\text{C}.$

Pin Capacitance

Table 14 lists the Stratix V device family pin capacitance.

Table 14. Pin Capacitance for Stratix V Devices

| Symbol | Description | | Unit |
|--------------------|--|---|------|
| C _{IOTB} | Input capacitance on the top and bottom I/O pins | 6 | pF |
| C _{IOLR} | Input capacitance on the left and right I/O pins | 6 | pF |
| C _{OUTFB} | Input capacitance on dual-purpose clock output and feedback pins | 6 | pF |

Hot Socketing

Table 15 lists the hot socketing specifications for Stratix V devices.

Table 15. Hot Socketing Specifications for Stratix V Devices

| Symbol | Description | Maximum |
|---------------------------|--|---------------------|
| I _{IOPIN (DC)} | DC current per I/O pin | 300 μΑ |
| I _{IOPIN (AC)} | AC current per I/O pin | 8 mA ⁽¹⁾ |
| I _{XCVR-TX (DC)} | DC current per transceiver transmitter pin | 100 mA |
| I _{XCVR-RX (DC)} | DC current per transceiver receiver pin | 50 mA |

Note to Table 15:

(1) The I/O ramp rate is 10 ns or more. For ramp rates faster than 10 ns, $|I_{IOPIN}| = C dv/dt$, in which C is the I/O pin capacitance and dv/dt is the slew rate.

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Table 18. Single-Ended SSTL, HSTL, and HSUL I/O Reference Voltage Specifications for Stratix V Devices

| I/O Standard | | V _{CCIO} (V) | | | V _{REF} (V) | | | V _{TT} (V) | |
|-------------------------|-------|-----------------------|-------|-----------------------------|-------------------------|-----------------------------|-----------------------------|----------------------------|-----------------------------|
| I/O Standard | Min | Тур | Max | Min | Тур | Max | Min | Тур | Мах |
| SSTL-2 Class I, II | 2.375 | 2.5 | 2.625 | 0.49 * V _{CCIO} | 0.5 * V _{CCIO} | 0.51 * V _{CCIO} | V _{REF} – 0.04 | V_{REF} | V _{REF} + 0.04 |
| SSTL-18 Class I, II | 1.71 | 1.8 | 1.89 | 0.833 | 0.9 | 0.969 | V _{REF} – 0.04 | V _{REF} | V _{REF} + 0.04 |
| SSTL-15 Class I, II | 1.425 | 1.5 | 1.575 | 0.49 * V _{CCIO} | 0.5 * V _{CCIO} | 0.51 * V _{CCIO} | 0.49 * V _{CCIO} | 0.5 * VCCIO | 0.51 * V _{CCIO} |
| SSTL-135 Class I, II | 1.283 | 1.35 | 1.418 | 0.49 * V _{CCIO} | 0.5 * V _{CCIO} | 0.51 * V _{CCIO} | 0.49 * V _{CCIO} | 0.5 * V _{CCIO} | 0.51 * V _{CCIO} |
| SSTL-125 Class I, II | 1.19 | 1.25 | 1.26 | 0.49 * V _{CCIO} | 0.5 * V _{CCIO} | 0.51 * V _{CCIO} | 0.49 * V _{CCIO} | 0.5 * VCCIO | 0.51 * V _{CCIO} |
| SSTL-12 Class I, II | 1.14 | 1.20 | 1.26 | 0.49 * V _{CCIO} | 0.5 * V _{CCIO} | 0.51 * V _{CCIO} | 0.49 * V _{CCIO} | 0.5 * VCCIO | 0.51 * V _{CCIO} |
| HSTL-18 Class I, II | 1.71 | 1.8 | 1.89 | 0.85 | 0.9 | 0.95 | _ | V _{CCIO} /2 | _ |
| HSTL-15 Class I, II | 1.425 | 1.5 | 1.575 | 0.68 | 0.75 | 0.9 | _ | V _{CCIO} /2 | _ |
| HSTL-12 Class I, II | 1.14 | 1.2 | 1.26 | 0.47 * V _{CCIO} | 0.5 * V _{CCIO} | 0.53 * V _{CCIO} | _ | V _{CCIO} /2 | _ |
| HSUL-12 | 1.14 | 1.2 | 1.3 | 0.49 * V _{CCIO} | 0.5 * V _{CCIO} | 0.51 * V _{CCIO} | _ | _ | _ |

Table 19. Single-Ended SSTL, HSTL, and HSUL I/O Standards Signal Specifications for Stratix V Devices (Part 1 of 2)

| I/O Standard | V _{IL(D(} | ; ₎ (V) | V _{IH(D} | _{C)} (V) | V _{IL(AC)} (V) | V _{IH(AC)} (V) | V _{OL} (V) | V _{OH} (V) | I (mA) | l _{oh} |
|-------------------------|--------------------|--------------------------|--------------------------|-------------------------|----------------------------|--------------------------|----------------------------|----------------------------|----------------------|-----------------|
| i/U Stanuaru | Min | Max | Min | Max | Max | Min | Max | Min | I _{ol} (mA) | (mA) |
| SSTL-2 Class I | -0.3 | V _{REF} – 0.15 | V _{REF} + 0.15 | V _{CCIO} + 0.3 | V _{REF} – 0.31 | V _{REF} + 0.31 | V _{TT} – 0.608 | V _{TT} + 0.608 | 8.1 | -8.1 |
| SSTL-2 Class II | -0.3 | V _{REF} – 0.15 | V _{REF} + 0.15 | V _{CCIO} + 0.3 | V _{REF} – 0.31 | V _{REF} + 0.31 | V _{TT} – 0.81 | V _{TT} + 0.81 | 16.2 | -16.2 |
| SSTL-18 Class I | -0.3 | V _{REF} – 0.125 | V _{REF} + 0.125 | V _{CCIO} + 0.3 | V _{REF} – 0.25 | V _{REF} + 0.25 | V _{TT} – 0.603 | V _{TT} + 0.603 | 6.7 | -6.7 |
| SSTL-18 Class II | -0.3 | V _{REF} – 0.125 | V _{REF} + 0.125 | V _{CCIO} + 0.3 | V _{REF} – 0.25 | V _{REF} + 0.25 | 0.28 | V _{CCIO} - 0.28 | 13.4 | -13.4 |
| SSTL-15 Class I | _ | V _{REF} – 0.1 | V _{REF} + 0.1 | _ | V _{REF} – 0.175 | V _{REF} + 0.175 | 0.2 * V _{CCIO} | 0.8 * V _{CCIO} | 8 | -8 |
| SSTL-15 Class II | _ | V _{REF} – 0.1 | V _{REF} + 0.1 | _ | V _{REF} – 0.175 | V _{REF} + 0.175 | 0.2 * V _{CCIO} | 0.8 * V _{CCIO} | 16 | -16 |
| SSTL-135 Class I, II | _ | V _{REF} – 0.09 | V _{REF} + 0.09 | _ | V _{REF} – 0.16 | V _{REF} + 0.16 | 0.2 * V _{CCIO} | 0.8 * V _{CCIO} | _ | _ |
| SSTL-125 Class I, II | _ | V _{REF} – 0.85 | V _{REF} + 0.85 | _ | V _{REF} – 0.15 | V _{REF} + 0.15 | 0.2 * V _{CCIO} | 0.8 * V _{CCIO} | _ | _ |
| SSTL-12 Class I, II | _ | V _{REF} – 0.1 | V _{REF} + 0.1 | _ | V _{REF} – 0.15 | V _{REF} + 0.15 | 0.2 * V _{CCIO} | 0.8 * V _{CCIO} | _ | _ |

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Table 21. Differential HSTL and HSUL I/O Standards for Stratix V Devices (Part 2 of 2)

| I/O | | V _{CCIO} (V) | | V _{DIF(} | | | V _{X(AC)} (V) | | | V _{CM(DC)} (V) | | | _(C) (V) |
|------------------------|------|-----------------------|------|-------------------|-------------------------|---------------------------------|---------------------------|---------------------------------|---------------------------|---------------------------|---------------------------|------|-----------------------------|
| Standard | Min | Тур | Max | Min | Max | Min | Тур | Max | Min | Тур | Max | Min | Max |
| HSTL-12 Class I, II | 1.14 | 1.2 | 1.26 | 0.16 | V _{CCIO} + 0.3 | _ | 0.5* V _{CCIO} | _ | 0.4* V _{CCIO} | 0.5* V _{CCIO} | 0.6* V _{CCIO} | 0.3 | V _{CCIO} + 0.48 |
| HSUL-12 | 1.14 | 1.2 | 1.3 | 0.26 | 0.26 | 0.5*V _{CCIO} - 0.12 | 0.5* V _{CCIO} | 0.5*V _{CCIO} + 0.12 | 0.4* V _{CCIO} | 0.5* V _{CCIO} | 0.6* V _{CCIO} | 0.44 | 0.44 |

Table 22. Differential I/O Standard Specifications for Stratix V Devices (7)

| I/O | Vc | _{CIO} (V) | (10) | | V _{ID} (mV) ⁽⁸⁾ | | | $V_{ICM(DC)}$ (V) | | V _o | _D (V) (| 6) | V | _{OCM} (V) | (6) |
|------------------------------|-------|--------------------|-------|-----|-------------------------------------|-----|------|--------------------------------|-------|----------------|--------------------|-----|-------|--------------------|-------|
| Standard | Min | Тур | Max | Min | Condition | Max | Min | Condition | Max | Min | Тур | Max | Min | Тур | Max |
| PCML | Trar | nsmitte | | | | | | of the high-s I/O pin speci | | | | | | | . For |
| 2.5 V | 2.375 | 2.5 | 2.625 | 100 | V _{CM} = | _ | 0.05 | D _{MAX} ≤ 700 Mbps | 1.8 | 0.247 | _ | 0.6 | 1.125 | 1.25 | 1.375 |
| LVDS (1) | 2.373 | 2.3 | 2.023 | 100 | 1.25 V | | 1.05 | D _{MAX} > 700 Mbps | 1.55 | 0.247 | _ | 0.6 | 1.125 | 1.25 | 1.375 |
| BLVDS (5) | 2.375 | 2.5 | 2.625 | 100 | _ | _ | _ | _ | _ | _ | _ | _ | _ | _ | _ |
| RSDS (HIO) ⁽²⁾ | 2.375 | 2.5 | 2.625 | 100 | V _{CM} = 1.25 V | _ | 0.3 | _ | 1.4 | 0.1 | 0.2 | 0.6 | 0.5 | 1.2 | 1.4 |
| Mini- LVDS (HIO) (3) | 2.375 | 2.5 | 2.625 | 200 | _ | 600 | 0.4 | _ | 1.325 | 0.25 | _ | 0.6 | 1 | 1.2 | 1.4 |
| LVPECL (4 | _ | _ | _ | 300 | _ | _ | 0.6 | D _{MAX} ≤ 700 Mbps | 1.8 | _ | _ | _ | _ | _ | _ |
|), (9) | _ | _ | _ | 300 | _ | _ | 1 | D _{MAX} > 700 Mbps | 1.6 | _ | _ | _ | _ | _ | _ |

Notes to Table 22:

- (1) For optimized LVDS receiver performance, the receiver voltage input range must be between 1.0 V to 1.6 V for data rates above 700 Mbps, and 0 V to 1.85 V for data rates below 700 Mbps.
- (2) For optimized RSDS receiver performance, the receiver voltage input range must be between 0.25 V to 1.45 V.
- (3) For optimized Mini-LVDS receiver performance, the receiver voltage input range must be between 0.3 V to 1.425 V.
- (4) For optimized LVPECL receiver performance, the receiver voltage input range must be between 0.85 V to 1.75 V for data rate above 700 Mbps and 0.45 V to 1.95 V for data rate below 700 Mbps.
- (5) There are no fixed V_{ICM} , V_{OD} , and V_{OCM} specifications for BLVDS. They depend on the system topology.
- (6) RL range: $90 \le RL \le 110 \Omega$.
- (7) The 1.4-V and 1.5-V PCML transceiver I/O standard specifications are described in "Transceiver Performance Specifications" on page 18.
- (8) The minimum VID value is applicable over the entire common mode range, VCM.
- (9) LVPECL is only supported on dedicated clock input pins.
- (10) Differential inputs are powered by VCCPD which requires 2.5 $\rm V.$

Power Consumption

Altera offers two ways to estimate power consumption for a design—the Excel-based Early Power Estimator and the Quartus[®] II PowerPlay Power Analyzer feature.

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You typically use the interactive Excel-based Early Power Estimator before designing the FPGA to get a magnitude estimate of the device power. The Quartus II PowerPlay Power Analyzer provides better quality estimates based on the specifics of the design after you complete place-and-route. The PowerPlay Power Analyzer can apply a combination of user-entered, simulation-derived, and estimated signal activities that, when combined with detailed circuit models, yields very accurate power estimates.

For more information about power estimation tools, refer to the *PowerPlay Early Power Estimator User Guide* and the *PowerPlay Power Analysis* chapter in the *Quartus II Handbook*.

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Switching Characteristics

This section provides performance characteristics of the Stratix V core and periphery blocks.

These characteristics can be designated as Preliminary or Final.

- Preliminary characteristics are created using simulation results, process data, and other known parameters. The title of these tables show the designation as "Preliminary."
- Final numbers are based on actual silicon characterization and testing. The numbers reflect the actual performance of the device under worst-case silicon process, voltage, and junction temperature conditions. There are no designations on finalized tables.

Transceiver Performance Specifications

This section describes transceiver performance specifications.

Table 23 lists the Stratix V GX and GS transceiver specifications.

Table 23. Transceiver Specifications for Stratix V GX and GS Devices (1) (Part 1 of 7)

| Symbol/ | Conditions | Transceiver Speed Grade 1 | | | Trar | sceive Grade | r Speed 2 | Tran | sceive Grade | r Speed 3 | Unit |
|--|---|------------------------------|-------|------------|----------|-----------------|-------------------|-----------|-----------------|--------------|---------|
| Description | | Min | Тур | Max | Min | Тур | Max | Min | Тур | Max | |
| Reference Clock | | | | | | | | | | | |
| Supported I/O Standards | Dedicated reference clock pin | 1.2-V | PCML, | 1.4-V PCM | L, 1.5-V | | 2.5-V PCM HCSL | IL, Diffe | rential | LVPECL, L\ | DS, and |
| Sidiludius | RX reference clock pin | | | 1.4-V PCMI | _, 1.5-V | PCML, | 2.5-V PCM | L, LVPE | CL, and | d LVDS | |
| Input Reference Clock Frequency (CMU PLL) (8) | _ | 40 | — | 710 | 40 | | 710 | 40 | _ | 710 | MHz |
| Input Reference Clock Frequency (ATX PLL) ⁽⁸⁾ | _ | 100 | | 710 | 100 | | 710 | 100 | _ | 710 | MHz |
| Rise time | Measure at ±60 mV of differential signal ⁽²⁶⁾ | _ | _ | 400 | _ | | 400 | _ | _ | 400 | ne |
| Fall time | Measure at ±60 mV of differential signal ⁽²⁶⁾ | _ | — | 400 | _ | _ | 400 | _ | _ | 400 | ps |
| Duty cycle | _ | 45 | _ | 55 | 45 | _ | 55 | 45 | _ | 55 | % |
| Spread-spectrum modulating clock frequency | PCI Express® (PCIe®) | 30 | _ | 33 | 30 | | 33 | 30 | _ | 33 | kHz |

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Table 23. Transceiver Specifications for Stratix V GX and GS Devices (1) (Part 5 of 7)

| Symbol/ | Conditions | Tra | nsceive Grade | r Speed 1 | Trai | nsceive Grade | r Speed 2 | Trai | Unit | | |
|---|---|-----|------------------|--------------|------|------------------|--------------|------|-----------------|--------------------------|------|
| Description | | Min | Тур | Max | Min | Тур | Max | Min | Тур | Max | |
| | DC Gain Setting = 0 | | 0 | _ | _ | 0 | | _ | 0 | _ | dB |
| | DC Gain Setting = 1 | | 2 | _ | _ | 2 | | _ | 2 | _ | dB |
| Programmable DC gain | DC Gain Setting = 2 | | 4 | _ | | 4 | _ | _ | 4 | _ | dB |
| | DC Gain Setting = 3 | _ | 6 | _ | _ | 6 | _ | _ | 6 | _ | dB |
| | DC Gain Setting = 4 | _ | 8 | _ | _ | 8 | _ | _ | 8 | _ | dB |
| Transmitter | | | | | | | | | | | |
| Supported I/O Standards | _ | | | | - | 1.4-V an | ıd 1.5-V PC | ML | | | |
| Data rate (Standard PCS) | _ | 600 | _ | 12200 | 600 | _ | 12200 | 600 | _ | 8500/ 10312.5 (24) | Mbps |
| Data rate (10G PCS) | _ | 600 | _ | 14100 | 600 | _ | 12500 | 600 | _ | 8500/ 10312.5 (24) | Mbps |
| | 85- Ω setting | | 85 ± 20% | _ | _ | 85 ± 20% | _ | _ | 85 ± 20% | _ | Ω |
| Differential on- | 100-Ω setting | | 100 ± 20% | _ | _ | 100 ± 20% | _ | _ | 100 ± 20% | _ | Ω |
| chip termination resistors | 120-Ω setting | _ | 120 ± 20% | _ | _ | 120 ± 20% | _ | _ | 120 ± 20% | _ | Ω |
| | 150-Ω setting | | 150 ± 20% | _ | _ | 150 ± 20% | _ | _ | 150 ± 20% | _ | Ω |
| V _{OCM} (AC coupled) | 0.65-V setting | _ | 650 | _ | _ | 650 | _ | _ | 650 | _ | mV |
| V _{OCM} (DC coupled) | _ | | 650 | _ | _ | 650 | _ | _ | 650 | _ | mV |
| Rise time (7) | 20% to 80% | 30 | _ | 160 | 30 | _ | 160 | 30 | _ | 160 | ps |
| Fall time ⁽⁷⁾ | 80% to 20% | 30 | _ | 160 | 30 | _ | 160 | 30 | | 160 | ps |
| Intra-differential pair skew | Tx V _{CM} = 0.5 V and slew rate of 15 ps | _ | _ | 15 | _ | _ | 15 | _ | _ | 15 | ps |
| Intra-transceiver block transmitter channel-to- channel skew | x6 PMA bonded mode | _ | _ | 120 | _ | _ | 120 | _ | _ | 120 | ps |

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Table 23. Transceiver Specifications for Stratix V GX and GS Devices (1) (Part 7 of 7)

| Symbol/ Description | Conditions | Transceiver Speed Grade 1 | | Transceiver Speed Grade 2 | | | Tran | Unit | | | |
|----------------------------|------------|------------------------------|-----|------------------------------|-----|-----|------|------|-----|-----|----|
| Description | | Min | Тур | Max | Min | Тур | Max | Min | Тур | Max | |
| t _{pll_lock} (16) | _ | _ | _ | 10 | _ | _ | 10 | _ | _ | 10 | μs |

Notes to Table 23:

- (1) Speed grades shown in Table 23 refer to the PMA Speed Grade in the device ordering code. The maximum data rate could be restricted by the Core/PCS speed grade. Contact your Altera Sales Representative for the maximum data rate specifications in each speed grade combination offered. For more information about device ordering codes, refer to the *Stratix V Device Overview*.
- (2) The reference clock common mode voltage is equal to the V_{CCR_GXB} power supply level.
- (3) This supply must be connected to 1.0 V if the transceiver is configured at a data rate > 6.5 Gbps, and to 1.05 V if configured at a data rate > 10.3 Gbps when DFE is used. For data rates up to 6.5 Gbps, you can connect this supply to 0.85 V.
- (4) This supply follows VCCR_GXB.
- (5) The device cannot tolerate prolonged operation at this absolute maximum.
- (6) The differential eye opening specification at the receiver input pins assumes that **Receiver Equalization** is disabled. If you enable **Receiver Equalization**, the receiver circuitry can tolerate a lower minimum eye opening, depending on the equalization level.
- (7) The Quartus II software automatically selects the appropriate slew rate depending on the configured data rate or functional mode.
- (8) The input reference clock frequency options depend on the data rate and the device speed grade.
- (9) The line data rate may be limited by PCS-FPGA interface speed grade.
- (10) Refer to Figure 1 for the GX channel AC gain curves. The total effective AC gain is the AC gain minus the DC gain.
- (11) t_{LTR} is the time required for the receive CDR to lock to the input reference clock frequency after coming out of reset.
- (12) t_{I TD} is time required for the receiver CDR to start recovering valid data after the rx_is_lockedtodata signal goes high.
- (13) t_{LTD_manual} is the time required for the receiver CDR to start recovering valid data after the rx_is_lockedtodata signal goes high when the CDR is functioning in the manual mode.
- (14) t_{LTR_LTD_manual} is the time the receiver CDR must be kept in lock to reference (LTR) mode after the rx_is_lockedtoref signal goes high when the CDR is functioning in the manual mode.
- (15) $t_{pll\ powerdown}$ is the PLL powerdown minimum pulse width.
- (16) t_{nll lock} is the time required for the transmitter CMU/ATX PLL to lock to the input reference clock frequency after coming out of reset.
- (17) To calculate the REFCLK rms phase jitter requirement for PCle at reference clock frequencies other than 100 MHz, use the following formula: REFCLK rms phase jitter at f(MHz) = REFCLK rms phase jitter at 100 MHz × 100/f.
- (18) The maximum peak to peak differential input voltage V_{ID} after device configuration is equal to 4 × (absolute V_{MAX} for receiver pin V_{ICM}).
- (19) For ES devices, R_{REF} is 2000 Ω ±1%.
- (20) To calculate the REFCLK phase noise requirement at frequencies other than 622 MHz, use the following formula: REFCLK phase noise at f(MHz) = REFCLK phase noise at 622 MHz + 20*log(f/622).
- (21) SFP/+ optical modules require the host interface to have RD+/- differentially terminated with 100 Ω. The internal OCT feature is available after the Stratix V FPGA configuration is completed. Altera recommends that FPGA configuration is completed before inserting the optical module. Otherwise, minimize unnecessary removal and insertion with unconfigured devices.
- (22) Refer to Figure 2.
- (23) For oversampling designs to support data rates less than the minimum specification, the CDR needs to be in LTR mode only.
- (24) I3YY devices can achieve data rates up to 10.3125 Gbps.
- (25) When you use fPLL as a TXPLL of the transceiver.
- (26) REFCLK performance requires to meet transmitter REFCLK phase noise specification.
- (27) Minimum eye opening of 85 mV is only for the unstressed input eye condition.

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Table 24 shows the maximum transmitter data rate for the clock network.

Table 24. Clock Network Maximum Data Rate Transmitter Specifications (1)

| | | ATX PLL | | | CMU PLL (2) |) | | fPLL | |
|-----------------------------------|----------------------------------|--------------------------|--|----------------------------------|--------------------------|-------------------------|----------------------------------|--------------------------|-------------------------------|
| Clock Network | Non- bonded Mode (Gbps) | Bonded Mode (Gbps) | Channel Span | Non- bonded Mode (Gbps) | Bonded Mode (Gbps) | Channel Span | Non- bonded Mode (Gbps) | Bonded Mode (Gbps) | Channel Span |
| x1 ⁽³⁾ | 14.1 | _ | 6 | 12.5 | _ | 6 | 3.125 | _ | 3 |
| x6 ⁽³⁾ | _ | 14.1 | 6 | _ | 12.5 | 6 | _ | 3.125 | 6 |
| x6 PLL Feedback ⁽⁴⁾ | _ | 14.1 | Side- wide | _ | 12.5 | Side- wide | _ | _ | _ |
| xN (PCIe) | _ | 8.0 | 8 | _ | 5.0 | 8 | _ | _ | _ |
| xN (Native PHY IP) | 8.0 | 8.0 | Up to 13 channels above and below PLL | 7.99 | 7.99 | Up to 13 channels above | 3.125 | 3.125 | Up to 13 channels above |
| XIV (IVALIVE PRY IP) | _ | 8.01 to 9.8304 | Up to 7 channels above and below PLL | 7.99 | 7.99 | and below PLL | J. 125 | 3.123 | and below PLL |

Notes to Table 24:

⁽¹⁾ Valid data rates below the maximum specified in this table depend on the reference clock frequency and the PLL counter settings. Check the MegaWizard message during the PHY IP instantiation.

⁽²⁾ ATX PLL is recommended at 8 Gbps and above data rates for improved jitter performance.

⁽³⁾ Channel span is within a transceiver bank.

⁽⁴⁾ Side-wide channel bonding is allowed up to the maximum supported by the PHY IP.

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Table 28. Transceiver Specifications for Stratix V GT Devices (Part 5 of 5) (1)

| Symbol/ Description | Conditions | | Transceivei peed Grade | | | Transceive Deed Grade | eed Grade 3 | |
|----------------------------|------------|-----|---------------------------|-----|-----|--------------------------|-------------|----|
| Description | | Min | Тур | Max | Min | Тур | Max | |
| t _{pll_lock} (14) | _ | _ | _ | 10 | _ | _ | 10 | μs |

Notes to Table 28:

- (1) Speed grades shown refer to the PMA Speed Grade in the device ordering code. The maximum data rate could be restricted by the Core/PCS speed grade. Contact your Altera Sales Representative for the maximum data rate specifications in each speed grade combination offered. For more information about device ordering codes, refer to the *Stratix V Device Overview*.
- (2) The reference clock common mode voltage is equal to the VCCR_GXB power supply level.
- (3) The device cannot tolerate prolonged operation at this absolute maximum.
- (4) The differential eye opening specification at the receiver input pins assumes that receiver equalization is disabled. If you enable receiver equalization, the receiver circuitry can tolerate a lower minimum eye opening, depending on the equalization level.
- (5) Refer to Figure 5 for the GT channel AC gain curves. The total effective AC gain is the AC gain minus the DC gain.
- (6) Refer to Figure 6 for the GT channel DC gain curves.
- (7) CFP2 optical modules require the host interface to have the receiver data pins differentially terminated with 100 Ω. The internal OCT feature is available after the Stratix V FPGA configuration is completed. Altera recommends that FPGA configuration is completed before inserting the optical module. Otherwise, minimize unnecessary removal and insertion with unconfigured devices.
- (8) Specifications for this parameter are the same as for Stratix V GX and GS devices. See Table 23 for specifications.
- (9) t_{LTB} is the time required for the receive CDR to lock to the input reference clock frequency after coming out of reset.
- (10) tLTD is time required for the receiver CDR to start recovering valid data after the rx is lockedtodata signal goes high.
- (11) t_{LTD_manual} is the time required for the receiver CDR to start recovering valid data after the rx_is_lockedtodata signal goes high when the CDR is functioning in the manual mode.
- (12) t_{LTR_LTD_manual} is the time the receiver CDR must be kept in lock to reference (LTR) mode after the rx_is_lockedtoref signal goes high when the CDR is functioning in the manual mode.
- (13) tpll powerdown is the PLL powerdown minimum pulse width.
- (14) tpll lock is the time required for the transmitter CMU/ATX PLL to lock to the input reference clock frequency after coming out of reset.
- (15) To calculate the REFCLK rms phase jitter requirement for PCle at reference clock frequencies other than 100 MHz, use the following formula: REFCLK rms phase jitter at f(MHz) = REFCLK rms phase jitter at 100 MHz × 100/f.
- (16) The maximum peak to peak differential input voltage V_{ID} after device configuration is equal to 4 × (absolute V_{MAX} for receiver pin V_{ICM}).
- (17) For ES devices, RREF is 2000 Ω ±1%.
- (18) To calculate the REFCLK phase noise requirement at frequencies other than 622 MHz, use the following formula: REFCLK phase noise at f(MHz) = REFCLK phase noise at 622 MHz + 20*log(f/622).
- (19) SFP/+ optical modules require the host interface to have RD+/- differentially terminated with 100 Ω. The internal OCT feature is available after the Stratix V FPGA configuration is completed. Altera recommends that FPGA configuration is completed before inserting the optical module. Otherwise, minimize unnecessary removal and insertion with unconfigured devices.
- (20) Refer to Figure 4.
- (21) For oversampling design to support data rates less than the minimum specification, the CDR needs to be in LTR mode only.
- (22) This supply follows VCCR_GXB for both GX and GT channels.
- (23) When you use fPLL as a TXPLL of the transceiver.

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PLL Specifications

Table 31 lists the Stratix V PLL specifications when operating in both the commercial junction temperature range (0° to 85°C) and the industrial junction temperature range (-40° to 100° C).

Table 31. PLL Specifications for Stratix V Devices (Part 1 of 3)

| Symbol | Parameter | Min | Тур | Max | Unit |
|---------------------------------|--|-----|-----|--------------------|------|
| | Input clock frequency (C1, C2, C2L, I2, and I2L speed grades) | 5 | _ | 800 (1) | MHz |
| f _{IN} | Input clock frequency (C3, I3, I3L, and I3YY speed grades) | 5 | _ | 800 (1) | MHz |
| | Input clock frequency (C4, I4 speed grades) | 5 | _ | 650 ⁽¹⁾ | MHz |
| INPFD | Input frequency to the PFD | 5 | _ | 325 | MHz |
| FINPFD | Fractional Input clock frequency to the PFD | 50 | _ | 160 | MHz |
| | PLL VCO operating range (C1, C2, C2L, I2, I2L speed grades) | 600 | _ | 1600 | MHz |
| f _{vco} ⁽⁹⁾ | PLL VCO operating range (C3, I3, I3L, I3YY speed grades) | 600 | _ | 1600 | MHz |
| | PLL VCO operating range (C4, I4 speed grades) | 600 | _ | 1300 | MHz |
| EINDUTY | Input clock or external feedback clock input duty cycle | 40 | _ | 60 | % |
| | Output frequency for an internal global or regional clock (C1, C2, C2L, I2, I2L speed grades) | _ | _ | 717 (2) | MHz |
| Гоит | Output frequency for an internal global or regional clock (C3, I3, I3L speed grades) | _ | _ | 650 ⁽²⁾ | MHz |
| | Output frequency for an internal global or regional clock (C4, I4 speed grades) | _ | _ | 580 ⁽²⁾ | MHz |
| | Output frequency for an external clock output (C1, C2, C2L, I2, I2L speed grades) | _ | _ | 800 (2) | MHz |
| f _{out_ext} | Output frequency for an external clock output (C3, I3, I3L speed grades) | _ | _ | 667 (2) | MHz |
| | Output frequency for an external clock output (C4, I4 speed grades) | _ | _ | 553 ⁽²⁾ | MHz |
| t _{оитриту} | Duty cycle for a dedicated external clock output (when set to 50%) | 45 | 50 | 55 | % |
| FCOMP | External feedback clock compensation time | _ | | 10 | ns |
| DYCONFIGCLK | Dynamic Configuration Clock used for mgmt_clk and scanclk | _ | _ | 100 | MHz |
| Lock | Time required to lock from the end-of-device configuration or deassertion of areset | _ | _ | 1 | ms |
| DLOCK | Time required to lock dynamically (after switchover or reconfiguring any non-post-scale counters/delays) | _ | _ | 1 | ms |
| | PLL closed-loop low bandwidth | | 0.3 | | MHz |
| : CLBW | PLL closed-loop medium bandwidth | | 1.5 | | MHz |
| | PLL closed-loop high bandwidth (7) | _ | 4 | _ | MHz |
| PLL_PSERR | Accuracy of PLL phase shift | | _ | ±50 | ps |
| ARESET | Minimum pulse width on the areset signal | 10 | _ | _ | ns |

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Table 31. PLL Specifications for Stratix V Devices (Part 2 of 3)

| Symbol | Parameter | Min | Тур | Max | Unit |
|--|---|------|---------|--|-----------|
| → (3) (4) | Input clock cycle-to-cycle jitter (f _{REF} ≥ 100 MHz) | _ | _ | 0.15 | UI (p-p) |
| t _{INCCJ} (3), (4) | Input clock cycle-to-cycle jitter (f _{REF} < 100 MHz) | -750 | | +750 | ps (p-p) |
| + (5) | Period Jitter for dedicated clock output ($f_{OUT} \ge 100 \text{ MHz}$) | _ | _ | 175 ⁽¹⁾ | ps (p-p) |
| t _{OUTPJ_DC} (5) | Period Jitter for dedicated clock output (f _{OUT} < 100 MHz) | _ | _ | 17.5 ⁽¹⁾ | mUI (p-p) |
| + (5) | Period Jitter for dedicated clock output in fractional PLL ($f_{OUT} \ge 100 \text{ MHz}$) | _ | _ | 250 ⁽¹¹⁾ , 175 ⁽¹²⁾ | ps (p-p) |
| t _{FOUTPJ_DC} (5) | Period Jitter for dedicated clock output in fractional PLL (f _{OUT} < 100 MHz) | _ | _ | 25 ⁽¹¹⁾ , 17.5 ⁽¹²⁾ | mUI (p-p) |
| + (5) | Cycle-to-Cycle Jitter for a dedicated clock output $(f_{OUT} \ge 100 \text{ MHz})$ | _ | _ | 175 | ps (p-p) |
| t _{outccj_dc} (5) | Cycle-to-Cycle Jitter for a dedicated clock output (f _{OUT} < 100 MHz) | _ | _ | 17.5 | mUI (p-p) |
| + (5) | Cycle-to-cycle Jitter for a dedicated clock output in fractional PLL ($f_{OUT} \ge 100 \text{ MHz}$) | _ | _ | 250 ⁽¹¹⁾ , 175 ⁽¹²⁾ | ps (p-p) |
| t _{FOUTCCJ_DC} ⁽⁵⁾ | Cycle-to-cycle Jitter for a dedicated clock output in fractional PLL (f _{OUT} < 100 MHz)+ | _ | _ | 25 ⁽¹¹⁾ , 17.5 ⁽¹²⁾ | mUI (p-p) |
| t _{OUTPJ_IO} (5), | Period Jitter for a clock output on a regular I/O in integer PLL ($f_{OUT} \ge 100 \text{ MHz}$) | _ | _ | 600 | ps (p-p) |
| (8) | Period Jitter for a clock output on a regular I/O (f _{OUT} < 100 MHz) | _ | _ | 60 | mUI (p-p) |
| t _{FOUTPJ 10} (5), | Period Jitter for a clock output on a regular I/O in fractional PLL ($f_{OUT} \ge 100 \text{ MHz}$) | _ | _ | 600 (10) | ps (p-p) |
| (8), (11) | Period Jitter for a clock output on a regular I/O in fractional PLL (f_{OUT} < 100 MHz) | _ | _ | 60 (10) | mUI (p-p) |
| t _{outccj_10} (5), | Cycle-to-cycle Jitter for a clock output on a regular I/O in integer PLL ($f_{OUT} \ge 100$ MHz) | _ | _ | 600 | ps (p-p) |
| (8) | Cycle-to-cycle Jitter for a clock output on a regular I/O in integer PLL (f_{OUT} < 100 MHz) | _ | _ | 60 (10) | mUI (p-p) |
| t _{FOUTCCJ_IO} | Cycle-to-cycle Jitter for a clock output on a regular I/O in fractional PLL ($f_{OUT} \ge 100$ MHz) | _ | _ | 600 (10) | ps (p-p) |
| (8), (11) | Cycle-to-cycle Jitter for a clock output on a regular I/O in fractional PLL (f_{OUT} < 100 MHz) | _ | _ | 60 | mUI (p-p) |
| t _{CASC_OUTPJ_DC} | Period Jitter for a dedicated clock output in cascaded PLLs ($f_{OUT} \ge 100 \text{ MHz}$) | _ | _ | 175 | ps (p-p) |
| (5), (6) | Period Jitter for a dedicated clock output in cascaded PLLs (f _{OUT} < 100 MHz) | _ | _ | 17.5 | mUI (p-p) |
| f _{DRIFT} | Frequency drift after PFDENA is disabled for a duration of 100 μs | _ | _ | ±10 | % |
| dK _{BIT} | Bit number of Delta Sigma Modulator (DSM) | 8 | 24 | 32 | Bits |
| k _{VALUE} | Numerator of Fraction | 128 | 8388608 | 2147483648 | _ |

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Table 36. High-Speed I/O Specifications for Stratix V Devices (1), (2) (Part 2 of 4)

| Cumbal | Conditions | C1 | | C2, C2L, I2, I2L | | | C3, I3, I3L, I3YY | | | C4,I4 | | | Unit | |
|---|--|-----|-----|------------------|-----|-----|-------------------|-----|-----|-------|-----|-----|------|------|
| Symbol | | Min | Тур | Max | Min | Тур | Max | Min | Тур | Max | Min | Тур | Max | |
| Transmitter | | | | | | | | | | | | | | |
| True Differential I/O Standards - f _{HSDR} (data rate) | SERDES factor J = 3 to 10 (9), (11), (12), (13), (14), (15), (16) | (6) | _ | 1600 | (6) | _ | 1434 | (6) | _ | 1250 | (6) | _ | 1050 | Mbps |
| | SERDES factor J ≥ 4 LVDS TX with DPA (12), (14), (15), (16) | (6) | _ | 1600 | (6) | _ | 1600 | (6) | _ | 1600 | (6) | | 1250 | Mbps |
| | SERDES factor J = 2, uses DDR Registers | (6) | _ | (7) | (6) | _ | (7) | (6) | _ | (7) | (6) | _ | (7) | Mbps |
| | SERDES factor J = 1, uses SDR Register | (6) | _ | (7) | (6) | _ | (7) | (6) | _ | (7) | (6) | _ | (7) | Mbps |
| Emulated Differential I/O Standards with Three External Output Resistor Networks - f _{HSDR} (data rate) (10) | SERDES factor J = 4 to 10 (17) | (6) | _ | 1100 | (6) | _ | 1100 | (6) | _ | 840 | (6) | | 840 | Mbps |
| t _{x Jitter} - True Differential | Total Jitter for Data Rate 600 Mbps - 1.25 Gbps | _ | _ | 160 | _ | _ | 160 | _ | _ | 160 | _ | _ | 160 | ps |
| I/O Standards | Total Jitter for Data Rate < 600 Mbps | _ | _ | 0.1 | _ | _ | 0.1 | _ | _ | 0.1 | _ | _ | 0.1 | UI |
| t _{x Jitter} - Emulated Differential I/O Standards | Total Jitter for Data Rate 600 Mbps - 1.25 Gbps | _ | _ | 300 | _ | _ | 300 | _ | _ | 300 | _ | _ | 325 | ps |
| with Three External Output Resistor Network | Total Jitter for Data Rate < 600 Mbps | _ | _ | 0.2 | _ | _ | 0.2 | _ | _ | 0.2 | _ | _ | 0.25 | UI |

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Table 36. High-Speed I/O Specifications for Stratix V Devices (1), (2) (Part 4 of 4)

| Cumbal | Conditions | C 1 | | C2, C2L, I2, I2L | | | C3, I3, I3L, I3YY | | | C4,14 | | | Unit | |
|-------------------------------|--|------------|-----|------------------|-----|-----|-------------------|-----|-----|-----------|-----|-----|-----------|----------|
| Symbol | | Min | Тур | Max | Min | Тур | Max | Min | Тур | Max | Min | Тур | Max | Unit |
| | SERDES factor J = 3 to 10 | (6) | _ | (8) | (6) | | (8) | (6) | | (8) | (6) | _ | (8) | Mbps |
| f _{HSDR} (data rate) | SERDES factor J = 2, uses DDR Registers | (6) | | (7) | (6) | | (7) | (6) | | (7) | (6) | | (7) | Mbps |
| | SERDES factor J = 1, uses SDR Register | (6) | _ | (7) | (6) | _ | (7) | (6) | _ | (7) | (6) | _ | (7) | Mbps |
| DPA Mode | DPA Mode | | | | | | | | | | | | | |
| DPA run length | _ | | _ | 1000 0 | | | 1000 0 | _ | | 1000 0 | _ | _ | 1000 0 | UI |
| Soft CDR mode | Soft CDR mode | | | | | | | | | | | | | |
| Soft-CDR PPM tolerance | _ | _ | _ | 300 | _ | _ | 300 | _ | _ | 300 | _ | _ | 300 | ± PPM |
| Non DPA Mode | Non DPA Mode | | | | | | | | | | | | | |
| Sampling Window | _ | _ | _ | 300 | _ | | 300 | _ | | 300 | _ | _ | 300 | ps |

Notes to Table 36:

- (1) When J = 3 to 10, use the serializer/deserializer (SERDES) block.
- (2) When J = 1 or 2, bypass the SERDES block.
- (3) This only applies to DPA and soft-CDR modes.
- (4) Clock Boost Factor (W) is the ratio between the input data rate to the input clock rate.
- (5) This is achieved by using the **LVDS** clock network.
- (6) The minimum specification depends on the clock source (for example, the PLL and clock pin) and the clock routing resource (global, regional, or local) that you use. The I/O differential buffer and input register do not have a minimum toggle rate.
- (7) The maximum ideal frequency is the SERDES factor (J) x the PLL maximum output frequency (fOUT) provided you can close the design timing and the signal integrity simulation is clean.
- (8) You can estimate the achievable maximum data rate for non-DPA mode by performing link timing closure analysis. You must consider the board skew margin, transmitter delay margin, and receiver sampling margin to determine the maximum data rate supported.
- (9) If the receiver with DPA enabled and transmitter are using shared PLLs, the minimum data rate is 150 Mbps.
- (10) You must calculate the leftover timing margin in the receiver by performing link timing closure analysis. You must consider the board skew margin, transmitter channel-to-channel skew, and receiver sampling margin to determine leftover timing margin.
- (11) The F_{MAX} specification is based on the fast clock used for serial data. The interface F_{MAX} is also dependent on the parallel clock domain which is design-dependent and requires timing analysis.
- (12) Stratix V RX LVDS will need DPA. For Stratix V TX LVDS, the receiver side component must have DPA.
- (13) Stratix V LVDS serialization and de-serialization factor needs to be x4 and above.
- (14) Requires package skew compensation with PCB trace length.
- (15) Do not mix single-ended I/O buffer within LVDS I/O bank.
- (16) Chip-to-chip communication only with a maximum load of 5 pF.
- (17) When using True LVDS RX channels for emulated LVDS TX channel, only serialization factors 1 and 2 are supported.

Page 56 Configuration Specification

Table 49. DCLK-to-DATA[] Ratio (1) (Part 2 of 2)

| Configuration Scheme | Decompression | Design Security | DCLK-to-DATA[] Ratio | | | |
|-------------------------|---------------|-----------------|-------------------------|--|--|--|
| | Disabled | Disabled | 1 | | | |
| FPP ×32 | Disabled | Enabled | 4 | | | |
| | Enabled | Disabled | 8 | | | |
| | Enabled | Enabled | 8 | | | |

Note to Table 49:

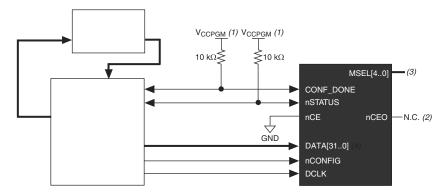
(1) Depending on the DCLK-to-DATA [] ratio, the host must send a DCLK frequency that is r times the data rate in bytes per second (Bps), or words per second (Wps). For example, in FPP ×16 when the DCLK-to-DATA [] ratio is 2, the DCLK frequency must be 2 times the data rate in Wps. Stratix V devices use the additional clock cycles to decrypt and decompress the configuration data.



If the DCLK-to-DATA[] ratio is greater than 1, at the end of configuration, you can only stop the DCLK (DCLK-to-DATA[] ratio -1) clock cycles after the last data is latched into the Stratix V device.

Figure 11 shows the configuration interface connections between the Stratix V device and a MAX II or MAX V device for single device configuration.

Figure 11. Single Device FPP Configuration Using an External Host



Notes to Figure 11:

- (1) Connect the resistor to a supply that provides an acceptable input signal for the Stratix V device. V_{CCPGM} must be high enough to meet the V_{IH} specification of the I/O on the device and the external host. Altera recommends powering up all configuration system I/Os with V_{CCPGM}.
- (2) You can leave the nceo pin unconnected or use it as a user I/O pin when it does not feed another device's nce pin.
- (3) The MSEL pin settings vary for different data width, configuration voltage standards, and POR delay. To connect MSEL, refer to the MSEL Pin Settings section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices" chapter.
- (4) If you use FPP $\times 8$, use DATA [7..0]. If you use FPP $\times 16$, use DATA [15..0].

Page 70 Document Revision History

Table 61. Document Revision History (Part 2 of 3)

| Date | Version | Changes |
|---------------|---------|---|
| | | ■ Added the I3YY speed grade and changed the data rates for the GX channel in Table 1. |
| | | ■ Added the I3YY speed grade to the V _{CC} description in Table 6. |
| | | ■ Added the I3YY speed grade to V _{CCHIP_L} , V _{CCHIP_R} , V _{CCHSSI_L} , and V _{CCHSSI_R} descriptions in Table 7. |
| | | ■ Added 240-Ω to Table 11. |
| | | ■ Changed CDR PPM tolerance in Table 23. |
| | | ■ Added additional max data rate for fPLL in Table 23. |
| | | ■ Added the I3YY speed grade and changed the data rates for transceiver speed grade 3 in Table 25. |
| | | ■ Added the I3YY speed grade and changed the data rates for transceiver speed grade 3 in Table 26. |
| | | ■ Changed CDR PPM tolerance in Table 28. |
| | | ■ Added additional max data rate for fPLL in Table 28. |
| | | ■ Changed the mode descriptions for MLAB and M20K in Table 33. |
| | 3.3 | ■ Changed the Max value of f _{HSCLK_OUT} for the C2, C2L, I2, I2L speed grades in Table 36. |
| November 2014 | | ■ Changed the frequency ranges for C1 and C2 in Table 39. |
| | | ■ Changed the .rbf file sizes for 5SGSD6 and 5SGSD8 in Table 47. |
| | | ■ Added note about nstatus to Table 50, Table 51, Table 54. |
| | | ■ Changed the available settings in Table 58. |
| | | ■ Changed the note in "Periphery Performance". |
| | | ■ Updated the "I/O Standard Specifications" section. |
| | | ■ Updated the "Raw Binary File Size" section. |
| | | ■ Updated the receiver voltage input range in Table 22. |
| | | ■ Updated the max frequency for the LVDS clock network in Table 36. |
| | | ■ Updated the DCLK note to Figure 11. |
| | | ■ Updated Table 23 VO _{CM} (DC Coupled) condition. |
| | | ■ Updated Table 6 and Table 7. |
| | | ■ Added the DCLK specification to Table 55. |
| | | ■ Updated the notes for Table 47. |
| | | ■ Updated the list of parameters for Table 56. |
| November 2013 | 3.2 | ■ Updated Table 28 |
| November 2013 | 3.1 | ■ Updated Table 33 |
| November 2013 | 3.0 | ■ Updated Table 23 and Table 28 |
| October 2013 | 2.9 | ■ Updated the "Transceiver Characterization" section |
| | 2.8 | ■ Updated Table 3, Table 12, Table 14, Table 19, Table 20, Table 23, Table 24, Table 28, Table 30, Table 31, Table 32, Table 33, Table 36, Table 39, Table 40, Table 41, Table 42, Table 47, Table 53, Table 58, and Table 59 |
| October 2013 | | ■ Added Figure 1 and Figure 3 |
| | | ■ Added the "Transceiver Characterization" section |
| | | ■ Removed all "Preliminary" designations. |